

Contents:

B-field source P 11 B-field source P 12 E-field source P 21

Case 175x140x32 mm Instructions



Technical data:

Pulser	P11 magnetic	P11 magnetic	P21 electric
Field strenth	ca. 1 mT	ca. 1 mT	ca. 100 kV/m
Pulse rise time	2 ns - 8 ns (adjustable)		
Pulse frequency	Single impulse or 5 kHz		
Dimension	(118 x 24 x 13) mm		
Weight	30 g		
Battery	1,5 Volt Micro		

MINI BURST GEN	P1 set	
Design	Description	Application
P 11 Localization of sensitive loops on printed circuit boards D 3mm	P 11 B pulser The magnetic field source generates a very fine B-field beam which is emitted from the tip of the probe (∅ > 1 mm). It is suitable for localizing spread and point-shaped weak points. The surface of printed circuit boards and components is scanned with the field beam. Due to the small diameter and the sharp focussing of the beam, a high resolution is possible. Critical conducting path sections, components and component connections can be localized.	
P 12 Lokalization of sensitive (C pins and circuit board conductors Circular magnetic field	P 12 B pulser The magnetic field source generates a very small circular magnetic pulse field (millimeter range). It can be placed upon individual conducting paths, IC pins, SMD components and thin lines (ribbon cables) as mini clip-on probe for the selective injection of interference currents and interference voltages. A unit often has many insensitive and few sensitive signal connections (conducting paths, IC pin). The sensitive ones can be identified quickly with the probe and be protected by corresponding layout changes.	NIIW
P 21 E-field sensitive conductors and components	P 21 E pulser The E-field source has a narrow, linear- shaped probe head and is designed for de-tecting weak points in the conducting path and component area of units. It is suitable for E-field injection on conducting paths, wires, pins and components; especially on individual SMD components such as resistors and capacitors. For the E-field injection, the probe is placed with its head upon individual conducting paths, SMD or wired components. Individual plug-in contacts and individual cores of ribbon cables can also be examined.	NAMAN A MANANA A MANA